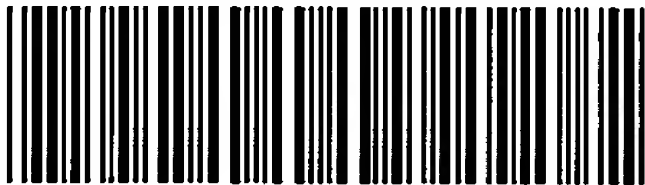


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/666,193	CHANG, YEN-JEN	
	Examiner	Art Unit	
	David D. Davis	2652	

SEARCHED			
Class	Subclass	Date	Examiner
720	609	3/21/2005	DDD
720	610	3/21/2005	DDD

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
720	609	3/21/2005	DDD

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR